



Product/Process Change Notice - PCN 19_0206 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: AD8226 Die and Data Sheet Revision

Publication Date: 23-Sep-2019

Effectivity Date: 26-Dec-2019 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release.

Description Of Change:

- 1) Modification of bias circuitry to improve start-up time.
- 2) Changes to the data sheet; less Human Body Model rating changed from 1.5kV to 1kV, in Absolute Maximum Rating Table 4 of ESD section.

Reason For Change:

New die revision aimed to improve the device performance by decreasing the start-up time of the bias circuitry at cold temperature setting.

Impact of the change (positive or negative) on fit, form, function & reliability:

No impact on fit, form, function and reliability when operated within data sheet specifications. There are no changes to bond pad locations and bonding diagram.

Product Identification *(this section will describe how to identify the changed material)*

Date codes starting 94 days after the publication of this PCN. Data Sheet changes will be included in Rev. D of the Product Data Sheet.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_19_0206_Rev_-_Qualification Results Summary_AD8226 Die Rev.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (9)

AD8226 / AD8226ARMZ	AD8226 / AD8226ARMZ-R7	AD8226 / AD8226ARMZ-RL	AD8226 / AD8226ARZ	AD8226 / AD8226ARZ-R7
AD8226 / AD8226ARZ-RL	AD8226 / AD8226BRMZ	AD8226 / AD8226BRMZ-R7	AD8226 / AD8226BRMZ-RL	

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	23-Sep-2019	26-Dec-2019	Initial Release.

Analog Devices, Inc.

DocId:6830 Parent DocId:None Layout Rev:7

Qualification Results Summary of AD8226 Die Revision

QUALIFICATION RESULTS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass 1500V
Electrostatic Discharge <i>Human Body Model</i>	JEDEC <i>JS-001-2010</i>	3/voltage	Pass 1000V
Latch-up	JEDEC <i>JESD78</i>	1 x 15	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1 x 30	Pass

*These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: 1. Bake – 24 hours at 125°C; 2. Soak – unbiased soak for 192 hours at 30°C, 60%RH; 3. Reflow – three passes through a reflow oven with a peak temperature of 260°C.